

ENGINEERING TRIPOS PART IIB

Friday 29 April 2005 2.30 to 4

Module 4B10

OPTOELECTRONIC TECHNOLOGIES

Answer not more than three questions

All questions carry the same number of marks

The approximate percentage of marks allocated to each part of a question is indicated in the right margin

Attachment:

Standard equations sheet (1 page)

You may not start to read the questions printed on the subsequent pages of this question paper until instructed that you may do so by the Invigilator



1	(a)	Exp	lain l	now p	oly	crysta	alline C	aAs is	initially	fo	ormed	from i	its	con	stituent
eleme	nts,	and	then	how	a	high	quality	pure	crystal	is	grown	ı usin	g	the	Liquid
Encap	sulat	ted C	zochr	alski 1	tecl	hnique	e .								

[30%]

(b) What basic processing of the crystal is carried out to form a substrate wafer, and what tests are carried out on the substrate wafer before beginning further processing to form photonic components?

[30%]

(c) The wafer is to be used for laser diode construction. Describe in detail what growth techniques might be used to form the epitaxial layers of the laser diode, explaining their relative advantages and disadvantages.

[40%]



2 (a) How might a Bragg reflector be implemented in a semiconductor laser? Describe with the aid of sketches how a distributed Bragg grating can be used to select a single optical frequency.							
(b) feedback	How is the manufacturing complexity and the laser affected by:	performance of a distributed					
	(i) The use of a first or second order grating?	e e					
	(ii) The use of a quarter wavelength phase shift?						
	(iii) The reflectivity of the facets?		[30%]				
(c) A distributed feedback laser with a characteristic temperature 80 K is to be used without temperature stabilisation with the following transmitter specifications:							
	Maximum laser temperature	85 ℃					
	Maximum forward current	90 mA					
	Maximum peak-to-peak modulation current	50 mA					
	Optical extinction ratio	10 dB					
	 (i) Assuming that the slope efficiency of the laser does not vary significantly, estimate the maximum and minimum value of threshold current over an operating range of 20 °C to 85 °C. (ii) Suggest reasons as to why the slope efficiency would be expected to reduce at higher temperatures. 						
	(iii) Describe the control electronics required	d to ensure the transmitter					

operates at constant mean power and constant extinction ratio for non-return-

to-zero data modulation.

[10%]



3 (a) Explain what is meant by transparency current density and threshold current density in a semiconductor laser.

[10%]

(b) The threshold current density can be expressed as a sum of the transparency current density and terms dependent on waveguide loss α and cavity length L:

$$J_{th} = J_o + \frac{v_g e d\alpha}{g\tau_s} - \frac{v_g e d. \log(R_r R_f)}{2g\tau_s} \cdot \frac{1}{L}$$

Explain the meaning of the parameters. How can this relationship be used to measure the losses in Fabry-Perot laser diodes?

[30%]

(c) A laser with the following parameters is fabricated for pumping an Erbium doped fibre amplifier.

Transparency current density	1 kA/cm ²
Waveguide loss	5 cm ⁻¹
Waveguide width	3 μm
Gain rate	$10^{-7} \text{ cm}^3/\text{s}$
Active layer thickness	10 nm
Transparency carrier density	$10^{18}\mathrm{cm}^{-3}$
Rear facet reflectivity	80%
Front facet reflectivity	1%
Internal injection efficiency	100%
Oscillating wavelength	980 nm
Refractive index	3.4

(i) How long must the laser cavity be to ensure an overall differential slope efficiency of at least 1 W/A?

[25%]

(ii) What current density is required to give 200 mW total output power?

[25%]

(iii) The series resistance is measured to be 1Ω . Estimate the proportion of electrical input power which is converted to optical output power at that current. How is the remaining power dissipated?

[10%]



4 (a) Sketch the structure for a high speed p-i-n photodiode for operation at 1.5 μm wavelength. Identify the mechanisms which impact the photodiode responsivity.	[20%]				
(b) A photodiode is connected to a component analyser with input impedance of 50 Ω . The optical responsitivity is measured to have a half power cut off frequency of 1 GHz. The capacitance of the photodiode is independently measured to be 2 pF.					
(i) What design changes might be implemented to reduce the capacitance?	[10%]				
(ii) What is the new half power cut off frequency if the capacitance is reduced to 500 fF?	[30%]				
(iii) What further design changes may be made to increase the cut off frequency?	[10%]				
(c) A p-i-n receiver is to be used in a long haul wavelength division multiplexed link which uses optical amplification at regular intervals. Identify the other photonic components required in the link and identify the aspects of the performance these components will have on signal quality after the receiver.					



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Standard Equations

1. Light Emitting Diode

$$P = \eta I \frac{hc}{e\lambda}$$

$$\frac{P(T)}{P(T_1)} = \exp\left(-\frac{(T_1 - T)}{T_o}\right)$$

$$P_T(t) = P_T(0) \exp(-\beta t)$$

$$\beta = \beta_0 \exp(-E_0 / kT)$$

2. Laser Diode

$$\frac{dn}{dt} = -g(n - n_o)P - \frac{n}{\tau_s} + \frac{J}{ed}$$

$$\frac{dP}{dt} = g(n - n_o)P + \frac{\beta n}{\tau_s} - \frac{P}{\tau_p}$$

$$\tau_p = \frac{n_r}{c} \left\{ \alpha + \frac{1}{2L} \ln \left(\frac{1}{R_1 R_2} \right) \right\}^{-1}$$

$$\delta \lambda = \frac{\lambda^2}{2L n_r}$$

3. Semiconductor optical amplifiers

$$\frac{dn}{dt} = \frac{I}{eV} - \frac{n}{\tau_s} - \Gamma g(n - n_o) P$$

$$\frac{dP}{dt} = \Gamma \beta \frac{n}{\tau_s} + \Gamma g(n - n_o) P$$

$$Power_{out} = \frac{c}{n_r} \frac{hc}{\lambda} A P_{out}$$

$$G' = g(n - n_o) \quad [s^{-1}]$$

$$G = \frac{n_r}{c} G' \quad [m^{-1}]$$

4. Receivers

$$\frac{dV}{dL} = \eta \frac{e}{hf} \cdot \frac{R}{(1 + j\omega RC)(1 + j\omega \tau)}$$

$$\left\langle \sigma_{Shot}^{2} \right\rangle = 2eIB_{e} \qquad \left\langle \sigma_{Thermal}^{2} \right\rangle = \frac{4kTB_{e}}{R}$$

5. Links

$$OSNR = \frac{i_{Signal}^{2}}{\sum \langle \sigma^{2} \rangle} \qquad \qquad \tau_{output} = \sqrt{\tau_{input}^{2} + \sum_{i=1}^{n} \tau_{system}^{2}}$$

$$Q = \frac{i_{ones} - i_{zeros}}{\sqrt{\sigma_{system}^{2} + \sqrt{\sigma_{system}^{2}}}} \qquad BER = \frac{1}{Q\sqrt{2\pi}} \exp\left(\frac{-Q^{2}}{2}\right)$$

Numerical Answers to 4B10

Q.2 (c)(i) 35 mA, 15.5 mA Q.3 (c)(i) 1280 µm, (ii) 8.31 kA/cm², (iii) 40% Q.4 (b)(ii) 2.16 GHz